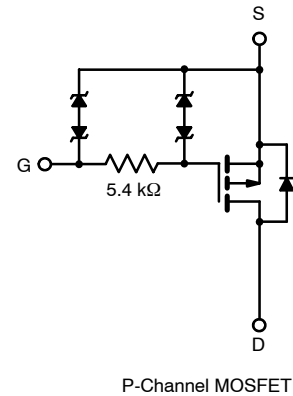
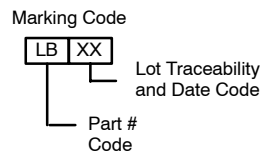
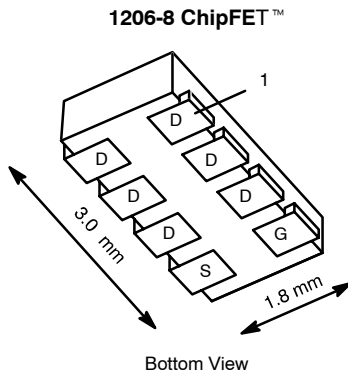




P-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A)
-20	0.062 @ $V_{GS} = -4.5$ V	-5.1
	0.068 @ $V_{GS} = -3.6$ V	-4.9
	0.085 @ $V_{GS} = -2.5$ V	-4.4
	0.120 @ $V_{GS} = -1.8$ V	-3.7



Ordering Information: Si5463EDC-T1

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)				
Parameter		Symbol	5 secs	Steady State
Drain-Source Voltage		V_{DS}	-20	
Gate-Source Voltage		V_{GS}	± 12	
Continuous Drain Current ($T_J = 150^\circ\text{C}$) ^a	$T_A = 25^\circ\text{C}$	I_D	-5.1	-3.8
	$T_A = 85^\circ\text{C}$		-3.7	-2.7
Pulsed Drain Current		I_{DM}	-15	
Continuous Source Current ^a		I_S	-1.9	-1.0
Maximum Power Dissipation ^a	$T_A = 25^\circ\text{C}$	P_D	2.3	1.25
	$T_A = 85^\circ\text{C}$		1.2	0.65
Operating Junction and Storage Temperature Range		T_J, T_{stg}	-55 to 150	
Soldering Recommendations (Peak Temperature) ^{c, d}			260	

THERMAL RESISTANCE RATINGS				
Parameter		Symbol	Typical	Maximum
Maximum Junction-to-Ambient ^a	$t \leq 5$ sec	R_{thJA}	45	55
	Steady State		84	100
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	20	25

Notes

- Surface Mounted on 1" x 1" FR4 Board.
- When using HBM. The MM rating is 300 V
- See Reliability Manual for profile. The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

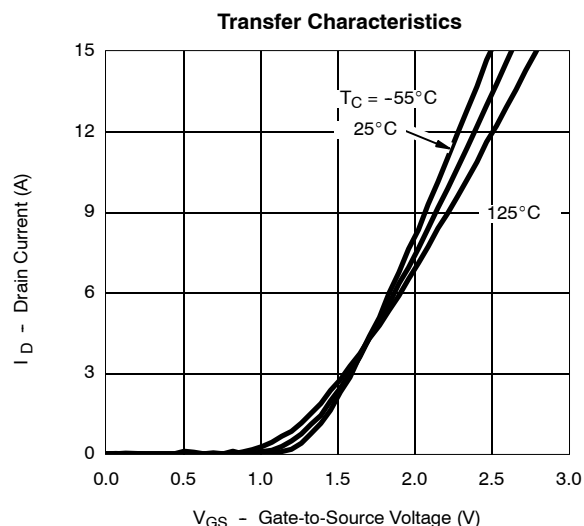
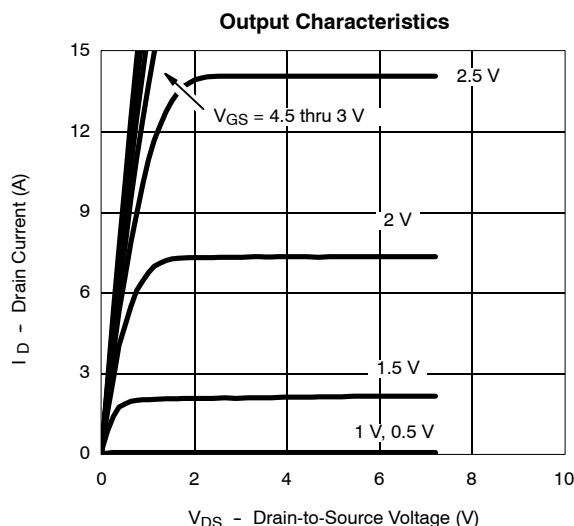
SPECIFICATIONS ($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = -250\ \mu\text{A}$	-0.45			V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\ \text{V}$, $V_{GS} = \pm 4.5\ \text{V}$			± 1.5	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -16\ \text{V}$, $V_{GS} = 0\ \text{V}$			-1	
		$V_{DS} = -16\ \text{V}$, $V_{GS} = 0\ \text{V}$, $T_J = 85^\circ\text{C}$			-5	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \leq -5\ \text{V}$, $V_{GS} = -4.5\ \text{V}$	-15			A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = -4.5\ \text{V}$, $I_D = -4.0\ \text{A}$		0.051	0.062	Ω
		$V_{GS} = -3.6\ \text{V}$, $I_D = -3.5\ \text{A}$		0.056	0.068	
		$V_{GS} = -2.5\ \text{V}$, $I_D = -3.0\ \text{A}$		0.070	0.085	
		$V_{GS} = -1.8\ \text{V}$, $I_D = -1.5\ \text{A}$		0.100	0.120	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -5\ \text{V}$, $I_D = -4.0\ \text{A}$		10		S
Diode Forward Voltage ^a	V_{SD}	$I_S = -1.0\ \text{A}$, $V_{GS} = 0\ \text{V}$		-0.75	-1.2	V
Dynamic^b						
Total Gate Charge	Q_g	$V_{DS} = -10\ \text{V}$, $V_{GS} = -4.5\ \text{V}$, $I_D = -4.0\ \text{A}$		9.7	15	nC
Gate-Source Charge	Q_{gs}			2.7		
Gate-Drain Charge	Q_{gd}			1.4		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -10\ \text{V}$, $R_L = 10\ \Omega$ $I_D \cong -1\ \text{A}$, $V_{GEN} = -4.5\ \text{V}$, $R_G = 6\ \Omega$		1.85	2.5	μs
Rise Time	t_r			3.2	4.5	
Turn-Off Delay Time	$t_{d(off)}$			1.9	2.5	
Fall Time	t_f			3.2	4.5	

Notes

a. Pulse test; pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$.

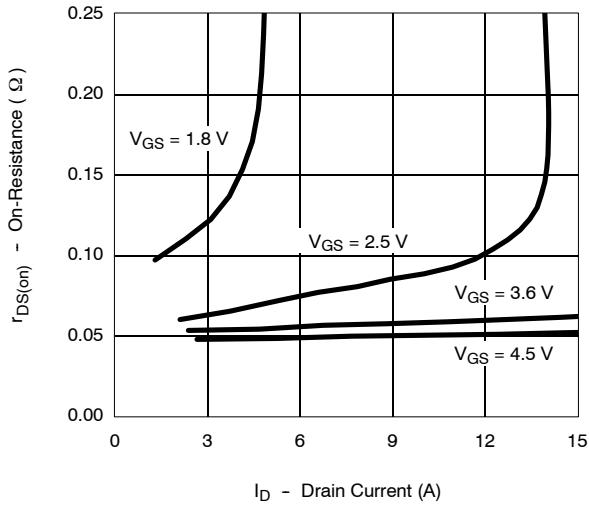
b. Guaranteed by design, not subject to production testing.

TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

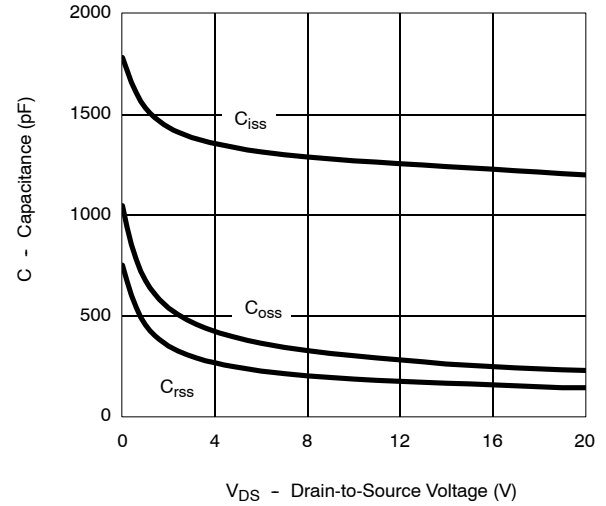


TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

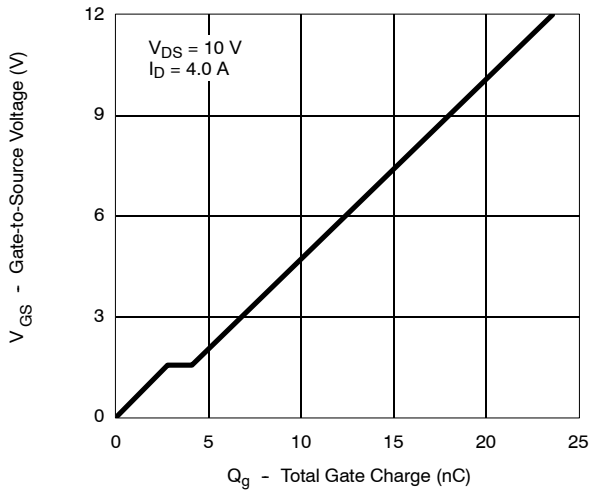
On-Resistance vs. Drain Current



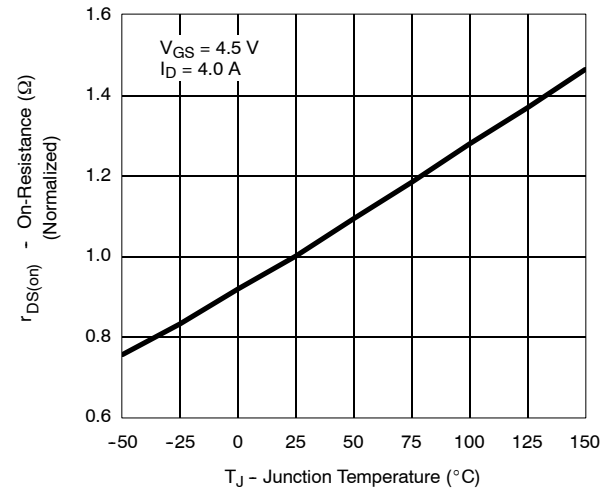
Capacitance



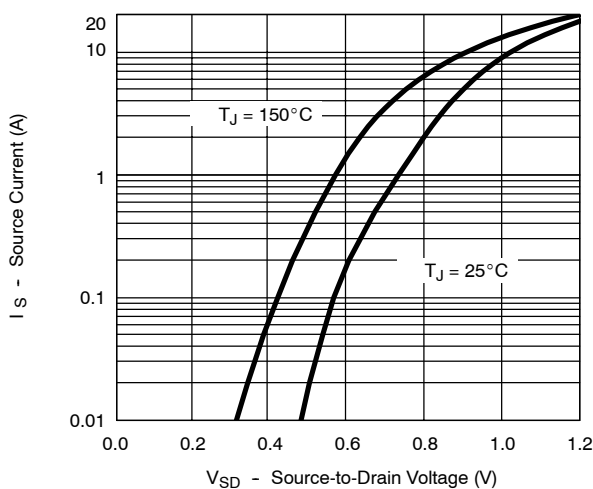
Gate Charge



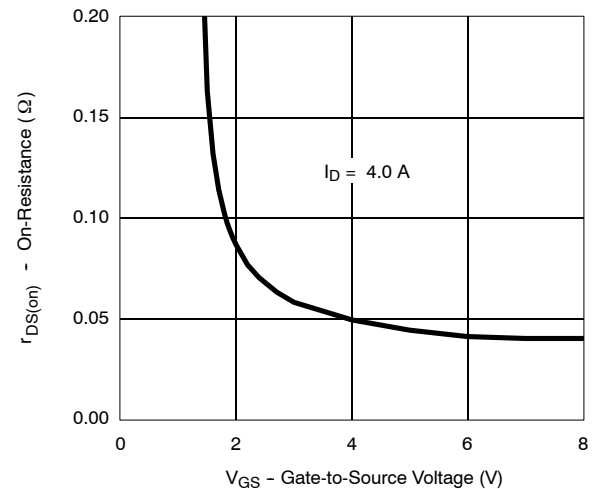
On-Resistance vs. Junction Temperature



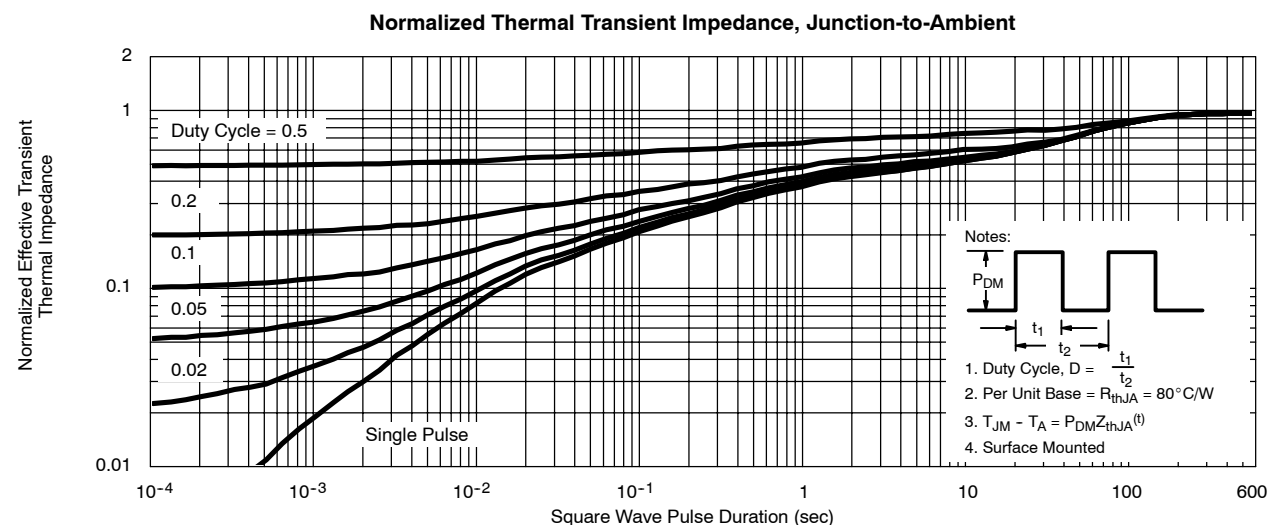
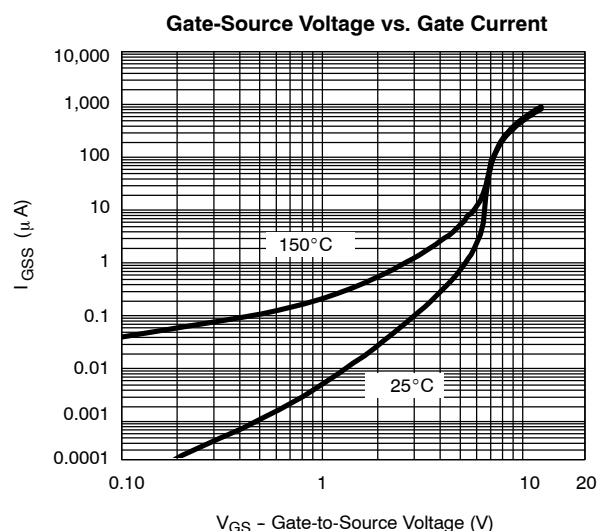
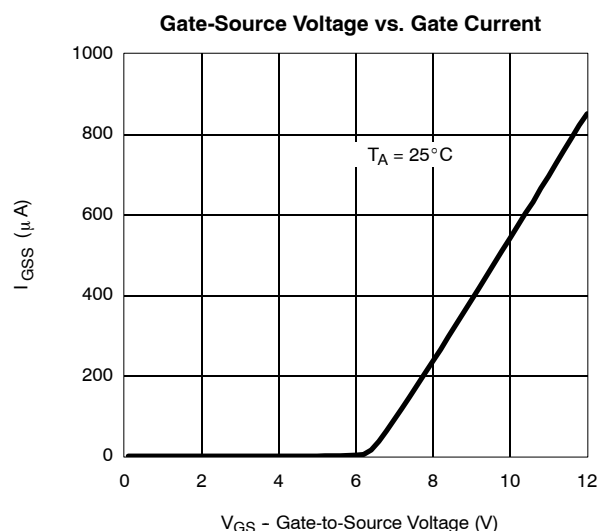
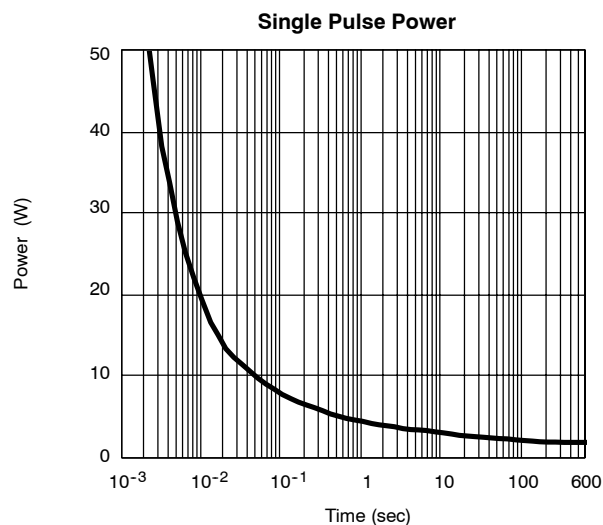
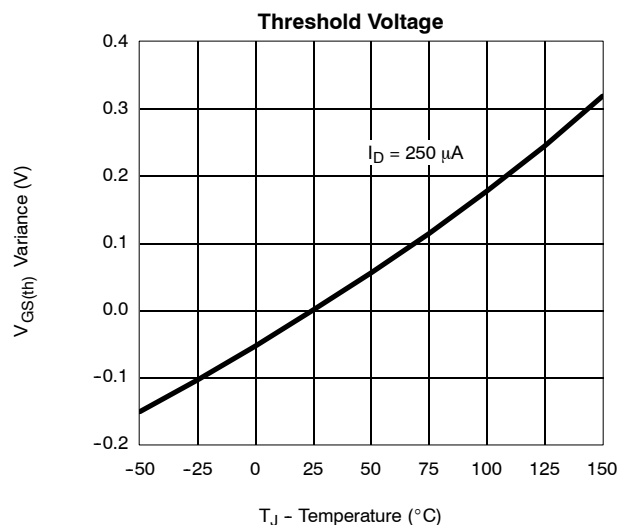
Source-Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage



TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)





TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

